September 1996

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SEMICONDUCTOR TM

# **NDT014**

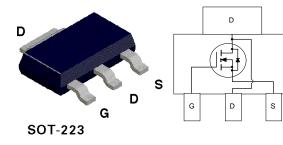
# **N-Channel Enhancement Mode Field Effect Transistor**

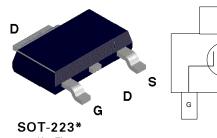
# **General Description**

Power SOT N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

# Features

- 2.7A, 60V.  $R_{DS(ON)} = 0.2\Omega @ V_{GS} = 10V.$
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.





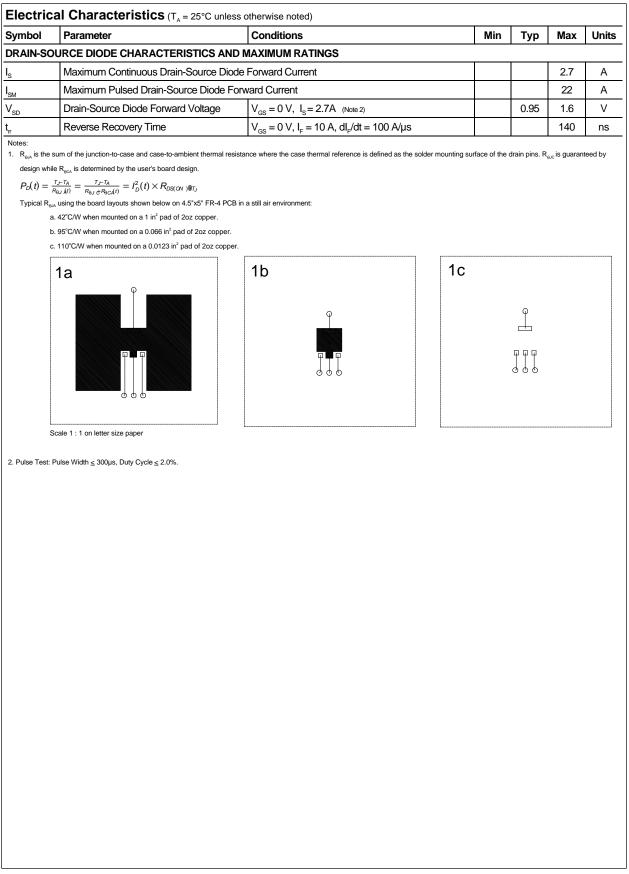
## (J23Z)

#### **Absolute Maximum Ratings** $T_A = 25^{\circ}C$ unless otherwise noted

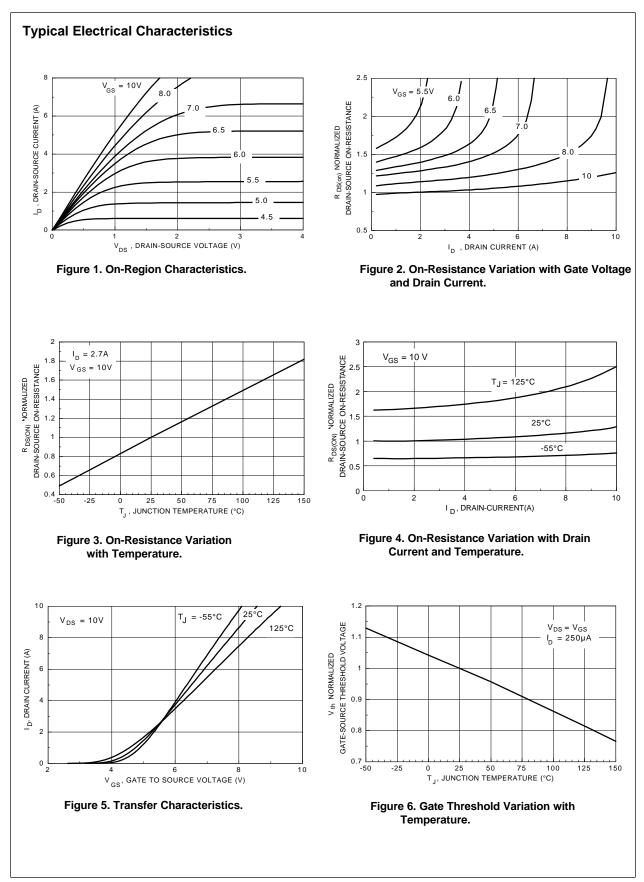
Symbol	Parameter		NDT014	Units
V <sub>DSS</sub>	Drain-Source Voltage		60	
V <sub>GSS</sub>	Gate-Source Voltage		±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	±2.7	A
	- Pulsed		±10	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	3	W
		(Note 1b)	1.3	
		(Note 1c)	1.1	
Г <sub>Ј</sub> ,Т <sub>STG</sub>	Operating and Storage Temperature Range		-65 to 150	°C
THERMA	L CHARACTERISTICS			
۶ <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°C/W
۲ <sub>өлс</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	12	°C/W
	tion J23Z for cropped center drain lead.			

Order option J23Z for cropped center drain lead.

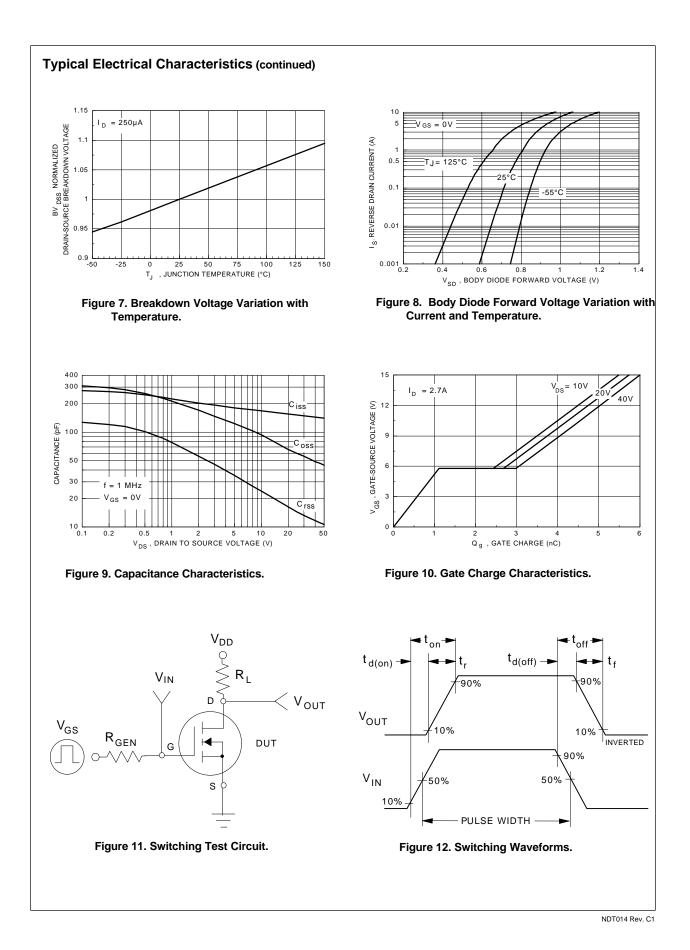
Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHA	RACTERISTICS					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	60			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			25	μA
		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}, \text{T}_{J} = 125^{\circ}\text{C}$			250	μA
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			100	nA
	Gate - Body Leakage, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
ON CHAF	ACTERISTICS (Note 2)		-			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \ \mu {\rm A}$	2	3	4	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1.6 \text{ A}$		0.18	0.2	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{\rm DS} = 25 \text{ V}, \text{ I}_{\rm D} = 1.6 \text{ A}$		2		S
DYNAMIC	CHARACTERISTICS		-			
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		155		pF
C <sub>oss</sub>	Output Capacitance			60		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			15		pF
SWITCHI	NG CHARACTERISTICS (Note 2)					
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 30 \text{ V}, \ \text{I}_{D} = 10 \text{ A},$		10	20	ns
t,	Turn - On Rise Time	$V_{\text{GEN}}$ = 10 V, $R_{\text{GEN}}$ = 24 $\Omega$		64	100	ns
t <sub>D(off)</sub>	Turn - Off Delay Time			10	20	ns
t,	Turn - Off Fall Time			10	20	ns
Q <sub>g</sub>	Total Gate Charge	$V_{\rm DS} = 48 \ V,$		5	11	nC
$Q_{gs}$	Gate-Source Charge	$I_{\rm D} = 10 \text{ A}, V_{\rm GS} = 10 \text{ V}$		1.2	3.1	nC
Q <sub>gd</sub>	Gate-Drain Charge			2	5.8	nC

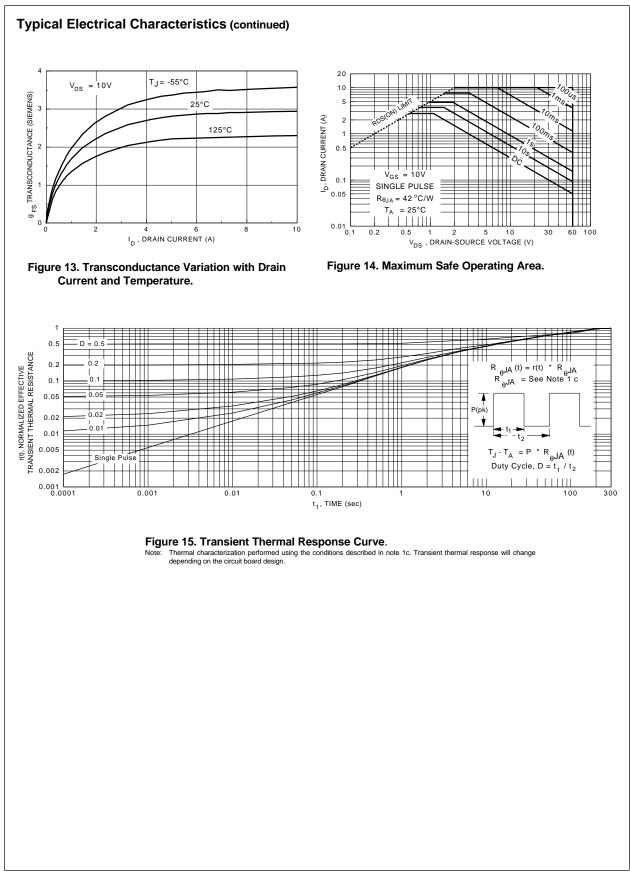


NDT014 Rev. C1



NDT014 Rev. C1





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